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U.S. DEPARTMENT OF COMMERCE

PATENT AND TRADEMARK OFFICE

| Sheet 1 of 2 | APPLICATION NO. | 1419.1085 | 10/651,210 | | |

LIST OF REFERENCES CITED BY APPLICANT

Kimitaka WATANABE et al.

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August 29, 2003

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$\sim \!$	AK	*Patent Abstracts of Japan; Publication No. 2003-173880, Published		-

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^{*} Reference already of record



FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

APPLICATION NO. ATTORNEY DOCKET NO. 10/651,210 1419.1085 FIRST NAMED INVENTOR

LIST OF REFERENCES CITED BY APPLICANT

Kimitaka WATANABE et al.

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92003, 2004 Staas & Halsey LLP

Revised July 2004



	ATTORNEY DOCKET NO.	APPLICATION NO.
·	1419.1085	10/651,210
LIST OF COPENDING APPLICATIONS	FIRST NAMED INVENTOR	
	Kimitaka WATANABE et	al.
	FILING DATE	GROUP ART UNIT
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The following, prior-filed, copending U.S. patent application(s) is/are listed in accordance with the duty of disclosure provisions of 37 CFR § 1.56, so that the Examiner may consider same should he deem any thereof to be material to examination of the subject application. Pursuant to 37 CFR § 1.98(a)(2)(iii), a copy of the identified copending application(s) is provided.

It is requested that the Examiner acknowledge his consideration of application(s) below-listed by initialling same in the space provided adjacent each such application and that the Examiner sign and date this form at the bottom thereof to confirm such consideration having been given.

This submission in no way represents an admission that any of the information listed herein constitutes prior art with respect to the subject application; and unless and until such prior art status is established, this submission is not a request that the information presented herein be printed on the face of any patent issuing from the subject application in which this information is being filed.

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U.S. DEPARTMENT OF COMMERCE

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CE 1419.1085

Sheet 1 of 2 APPLICATION NO.

PATENT AND TRADEMARK OFFICE

FIRST NAMED INVENTOR

10/651,210

LIST OF REFERENCES CITED BY APPLICANT

Kimitaka WATANABE

GROUP ART UNIT

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August 29, 2003

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